

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: A. Bhavnagarwala et al.

Examiner: West, Jeffrey R.

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For: **CIRCUITS AND METHODS FOR CHARACTERIZING RANDOM
VARIATIONS IN DEVICE CHARACTERISTICS IN SEMICONDUCTOR
INTEGRATED CIRCUITS**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

AMENDMENT UNDER 37 CFR 1.116

This paper is in response to the Decision on Appeal dated March 23, 2011.